



ALPHA & OMEGA
SEMICONDUCTOR

AOTS21115C
20V P-Channel MOSFET

General Description

- Trench Power MOSFET technology
- Low $R_{DS(ON)}$
- Low Gate Charge
- RoHS and Halogen-Free Compliant

Applications

- This device is ideal for Load Switch

Product Summary

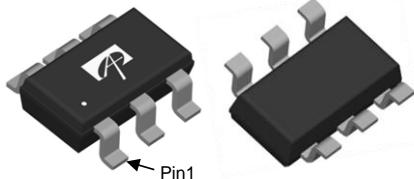
V_{DS}	-20V
I_D (at $V_{GS}=-4.5V$)	-6.6A
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$)	< 40mΩ
$R_{DS(ON)}$ (at $V_{GS}=-2.5V$)	< 55mΩ
$R_{DS(ON)}$ (at $V_{GS}=-1.8V$)	< 72mΩ

Typical ESD protection

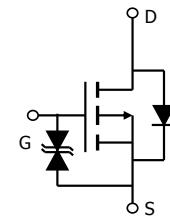
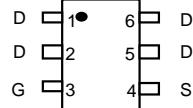
HBM Class 2



TSOP6
Top View Bottom View



Top View



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOTS21115C	TSOP-6	Tape & Reel	3000

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 8	V
Continuous Drain Current ^A	I_D	-6.6	A
Current ^B		-5.1	
Pulsed Drain Current ^C	I_{DM}	-26	
Power Dissipation ^B	P_D	2.5	W
Power Dissipation ^B		1.6	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	42	50	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		68	85	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	23	30	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}$, $V_{GS}=0\text{V}$	-20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-20\text{V}$, $V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 8\text{V}$			± 10	μA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=-250\mu\text{A}$	-0.15	-0.55	-0.95	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}$, $I_D=-6.6\text{A}$ $T_J=125^\circ\text{C}$	33	40		$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}$, $I_D=-5.6\text{A}$		42	55	$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}$, $I_D=-4.9\text{A}$		54	72	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}$, $I_D=-6.6\text{A}$		20		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}$, $V_{GS}=0\text{V}$		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current				-3	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=-10\text{V}$, $f=1\text{MHz}$		930		pF
C_{oss}	Output Capacitance			90		pF
C_{rss}	Reverse Transfer Capacitance			80		pF
R_g	Gate resistance	$f=1\text{MHz}$		15	30	Ω
SWITCHING PARAMETERS						
$Q_g(4.5\text{V})$	Total Gate Charge	$V_{GS}=-4.5\text{V}$, $V_{DS}=-10\text{V}$, $I_D=-6.6\text{A}$		8.5	17	nC
Q_{gs}	Gate Source Charge			1		nC
Q_{gd}	Gate Drain Charge			2.5		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=-4.5\text{V}$, $V_{DS}=-10\text{V}$, $R_L=1.52\Omega$, $R_{\text{GEN}}=3\Omega$		12		ns
t_r	Turn-On Rise Time			11		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			82		ns
t_f	Turn-Off Fall Time			35		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-6.6\text{A}$, $dI/dt=500\text{A}/\mu\text{s}$		25		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-6.6\text{A}$, $dI/dt=500\text{A}/\mu\text{s}$		37		nC

A. The value of R_{VJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

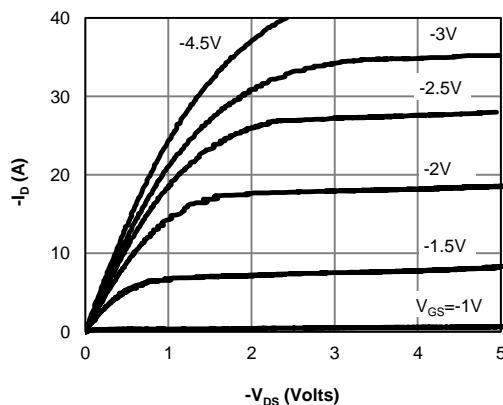
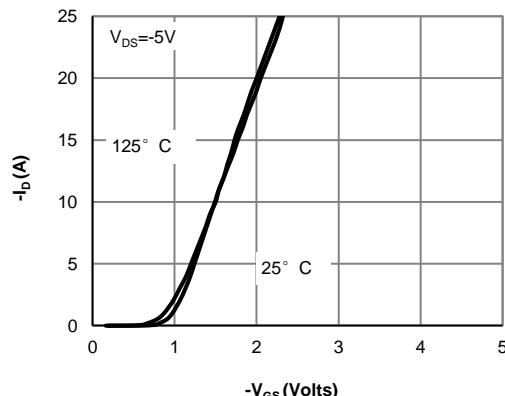
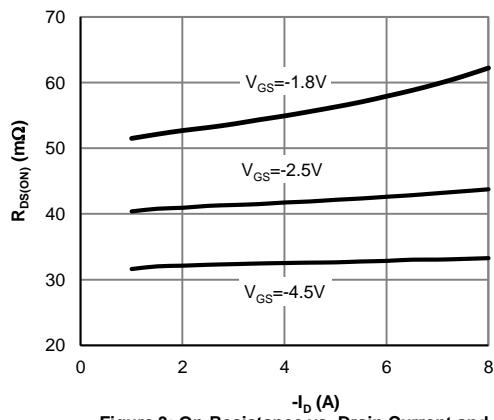
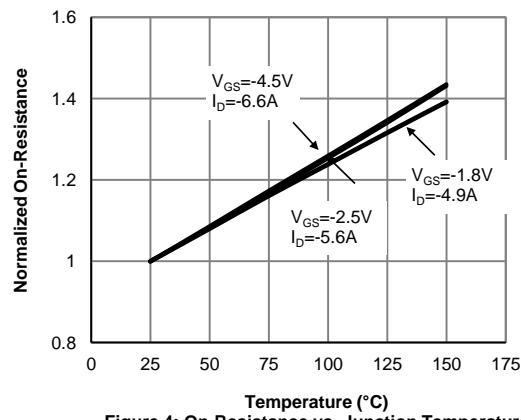
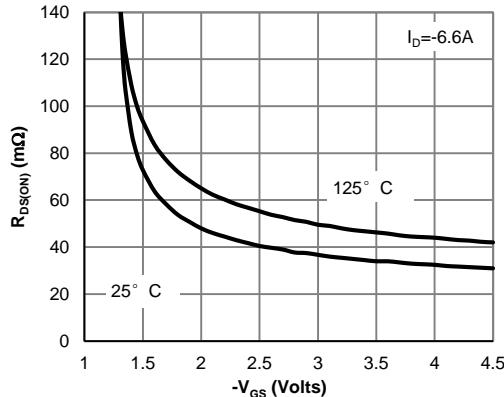
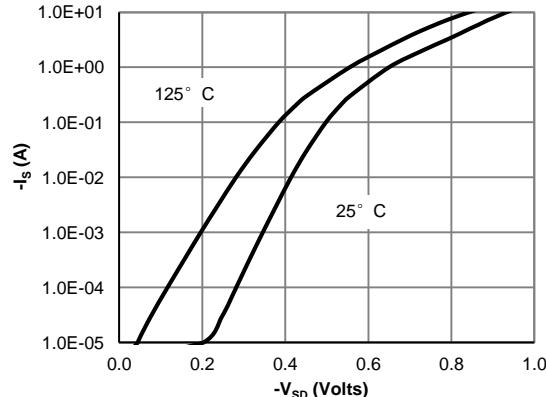
C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

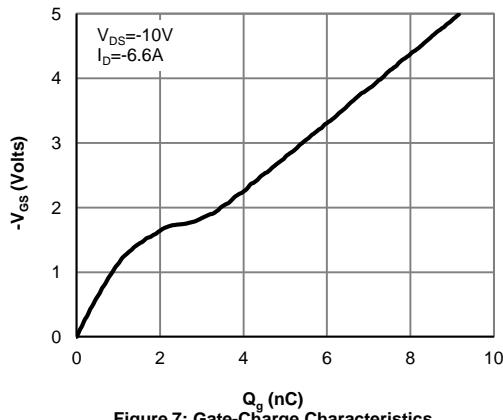
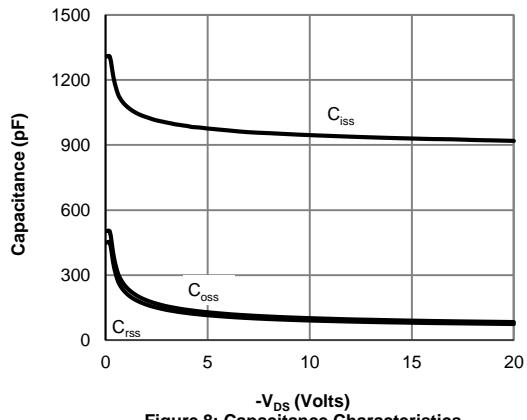
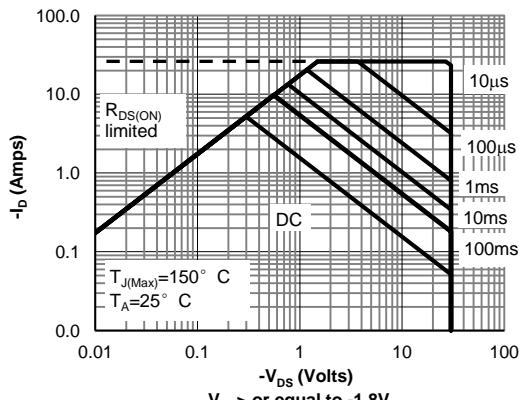
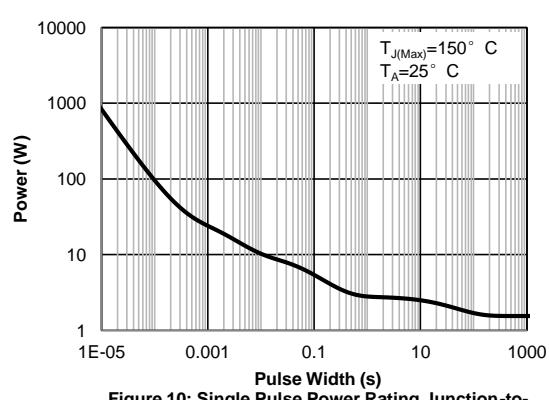
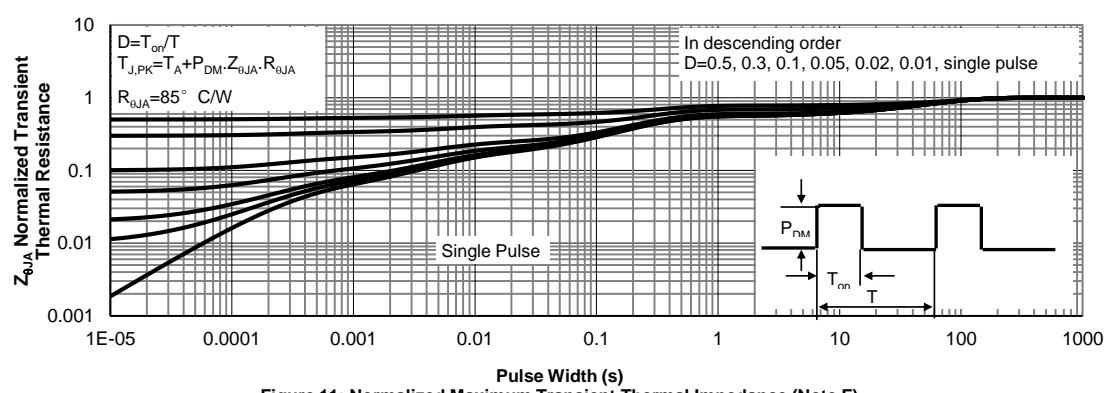
D. The R_{VJA} is the sum of the thermal impedance from junction to lead $R_{V JL}$ and lead to ambient.

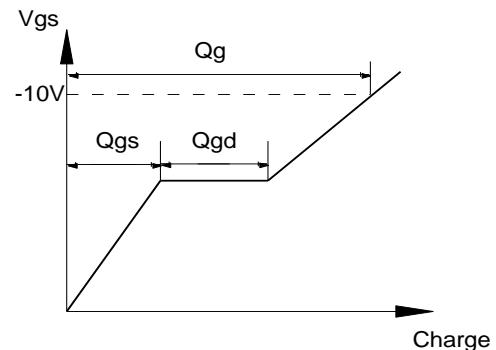
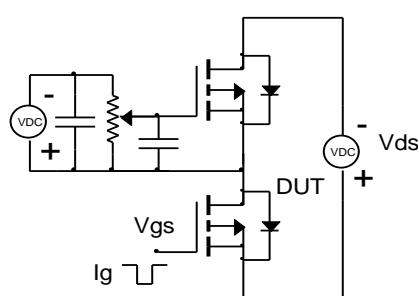
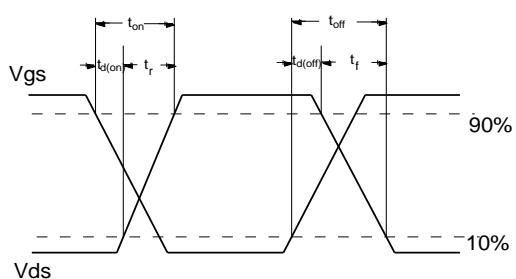
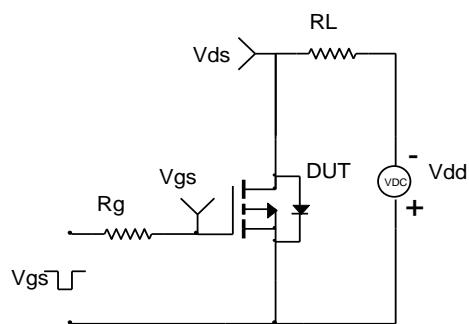
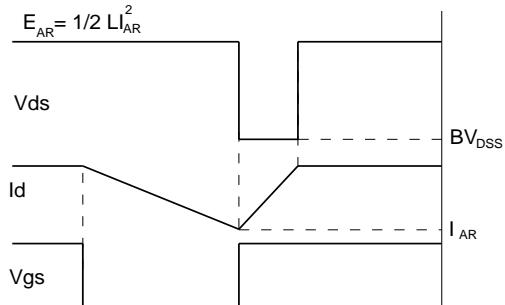
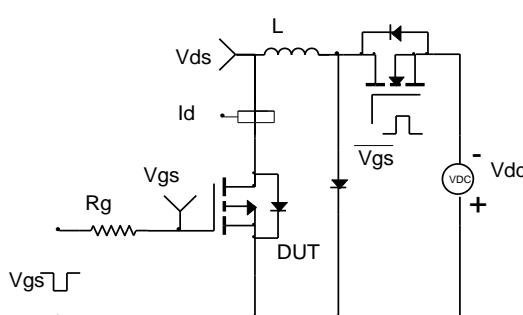
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
